

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/605,602	WANG, SUNG-FEI	
Examiner	Art Unit	
Sing P. Chan	1734	

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Class	Subclass	Date	Examiner
156	60, 250, 256, 267,307.3, 308.2	10/27/2005	SPC
156	309.6	10/27/2005	SPC
165	72-74,79	10/27/2005	SPC
165	80.1-80.3	10/27/2005	SPC
165	185	10/27/2005	SPC
165	DIG515	10/27/2005	SPC
D13	179	10/27/2005	SPC
257	706,707	10/27/2005	SPC
361	707, 710	10/27/2005	SPC
361	717-720	10/27/2005	SPC
361	600, 679	10/27/2005	SPC
361	688,704	10/27/2005	SPC
257	704, 712	10/27/2005	SPC

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
156	60, 250	10/27/2005	SPC
156	256, 267	10/27/2005	SPC
156	307.3	10/27/2005	SPC
165/72-74, 7	2, 309.6; 9, 80.1-80.3, IG 515	10/27/2005	SPC

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
Text and image search on EAST	10/27/2005	SPC	
Inventor search on EAST and PALM on Wang Sung-Fei	10/27/2005	SPC	
PGPUB Text search, Interference Searched	10/27/2005	SPC	

Search Notes (continued)

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D13	179	10/27/2005	SPC
257	704, 706	10/27/2005	SPC
257	707	10/27/2005	SPC
	10, 717-720, 688, 704	10/27/2005	SPC

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